

BRUKER EDXRF NEW PRODUCT RELEASES AND NEWS 2010

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NEW S2 RANGER with XFlash® LE:

The direct excitation EDXRF S2 RANGER is now available with the unique XFlash® LE silicon drift detector specific for the ultimate detection of light elements (LE). In the bench top EDXRF class the light element excitation is limited by the available current and generator power. Retaining the power level of 50Watts, we improved the performance dramatically by using a new 4th generation XFlash® LE detector. The All-In-One design of the S2 RANGER, with built in vacuum pump, can now convince by measuring Feldspars as fusions as well as many other industrial minerals. This increase in performance extends the applicability of bench top direct excitation EDXRF for applications involving Sodium (Na) and Magnesium (Mg) in industrial minerals and cement matrix prepared as either pellets or fusions.

NEW SPECTRA 7.0

New SPECTRA Software for the mobile ARTAX with XFLASH™ detection technology extends the functionality and adds full quantification support including empirical and fundamental parameter based matrix corrections. The software SPECTRA 7.0 offers faster deconvolution of ARTAX XFLASH™ spectra, fitting for low atomic elements down to Sodium (Na) and improved overlay corrections.

ACADEMIA TRAINING PACKAGE

Combining materials used in the last 5 years from seminars teaching Art and Conservation Scientists, Bruker XRF in-house and onsite training classes as well as new materials developed with academia, Bruker AXS is offering a complete ED XRF/ TXRF package for use in teaching and academia. The package consists of commented power points slides, examples as well as exercises with solutions. In addition it contains a freely distributable version of the SPECTRA software, which students can use to perform the exercises as well as to process their own data. Completing the solution is either the Bruker S2 RANGER EDX, S2 PICOFOX TXRF or the TRACER hand held EDXRF respectively.

The unique hand held TRACER unit, which employs Bruker's own XFlash™ Silicon Drift Detector technology, is ideally suited for the task since it allows full control over excitation as well as beam tuning using primary beam filters and targets. The patented vacuum technology allows the analysis of light elements, even in the field. The TRACER offers conventional bench top capabilities in hand held format, allowing users to make their own calibrations in their lab and apply them in the field.